

Notice of References Cited	Application/Control No. 10/686,841	Applicant(s)/Patent Under Reexamination LAMBERTON ET AL.	
	Examiner Kevin M. Bernatz	Art Unit 1773	Page 1 of 1

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	C	US-6,132,892	10-2000	Yoshikawa et al.	428/812
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NON-PATENT DOCUMENTS

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	U	Kong et al. (Mag. Conf, 2002, INTERMAG Europe 2002, Digest Papers)			
	V	Komuro et al. (J. Appl. Phys., 67(9), May 1990, 5126-5130)			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.